FIG. 1A

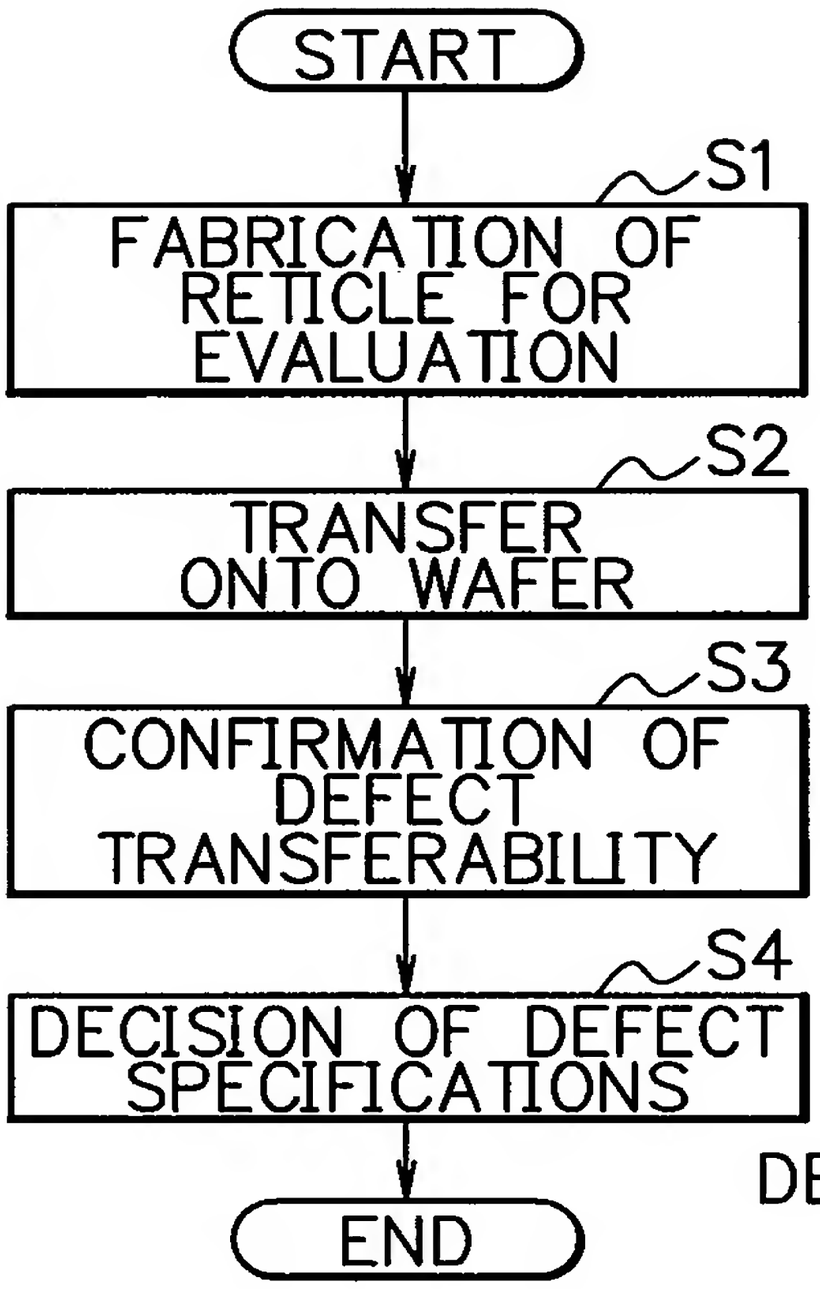
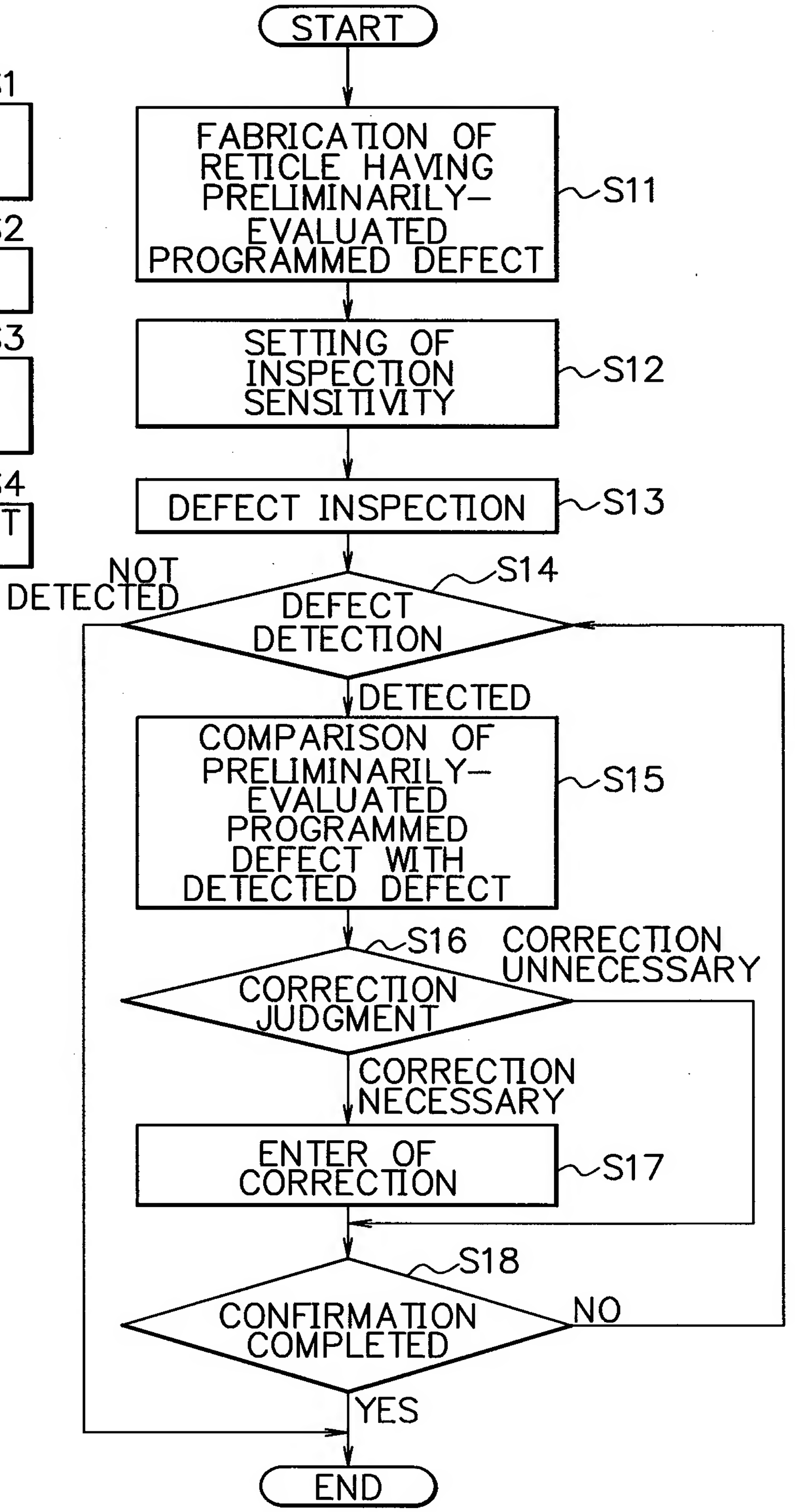

START
S1
FABRICATION OF RETICLE FOR EVALUATION
S2
TRANSFER ONTO WAFER
S3
CONFIRMATION OF DEFECT TRANSFERABILITY
S4
DECISION OF DEFECT SPECIFICATIONS
END

FIG. 1B


START
FABRICATION OF RETICLE HAVING PRELIMINARILY-EVALUATED PROGRAMMED DEFECT
S11
SETTING OF INSPECTION SENSITIVITY
S12
DEFECT INSPECTION
S13
S14
DEFECT DETECTION
NOT DETECTED
DETECTED
COMPARISON OF PRELIMINARILY-EVALUATED PROGRAMMED DEFECT WITH DETECTED DEFECT
S15
S16
CORRECTION JUDGMENT
CORRECTION UNNECESSARY
CORRECTION NECESSARY
ENTER OF CORRECTION
S17
S18
CONFIRMATION COMPLETED
NO
YES
END

F I G. 2A

F I G. 2B

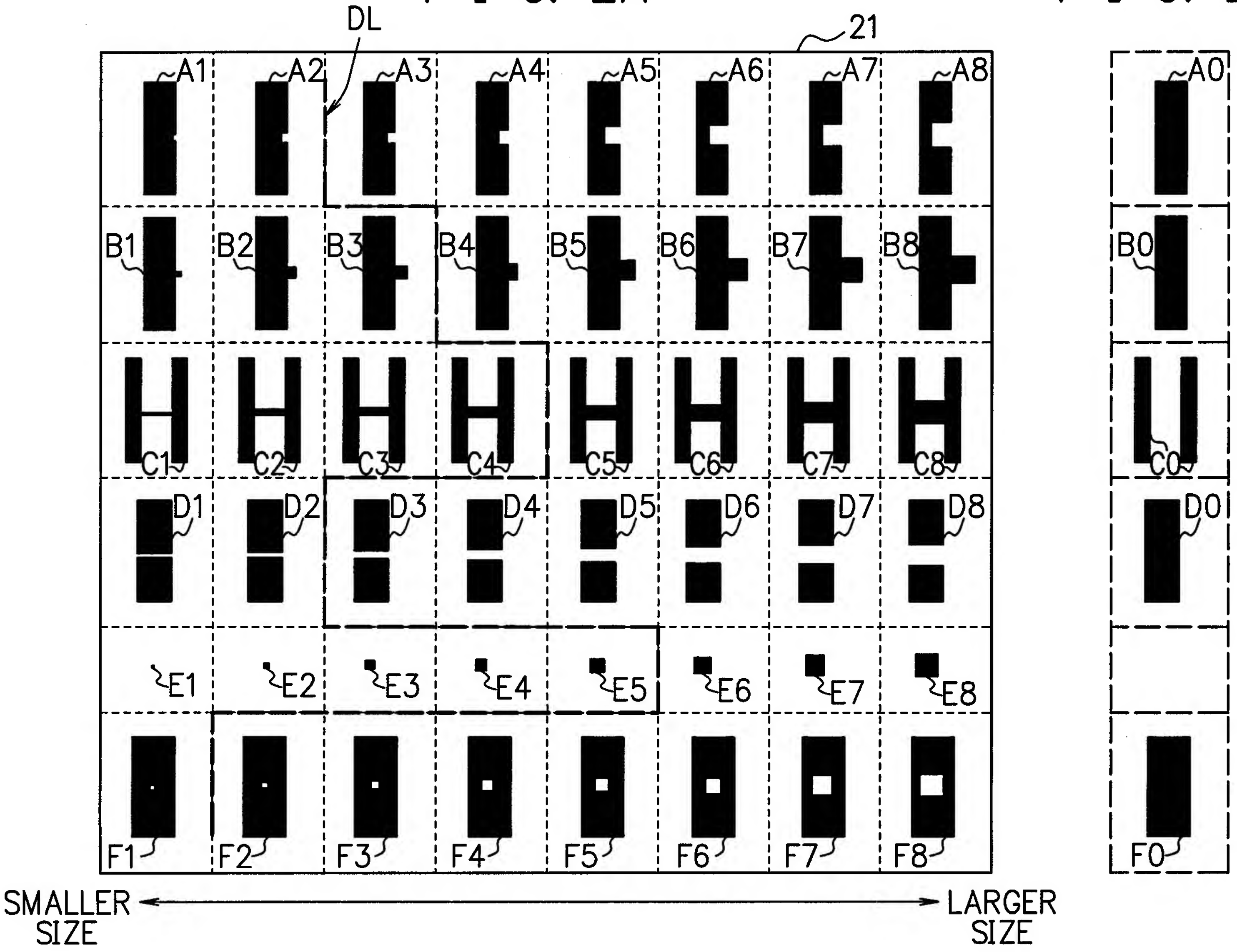

DL
21
A1
A2
A3
A4
A5
A6
A7
A8
A0
B1
B2
B3
B4
B5
B6
B7
B8
B0
C1
C2
C3
C4
C5
C6
C7
C8
C0
D1
D2
D3
D4
D5
D6
D7
D8
D0
E1
E2
E3
E4
E5
E6
E7
E8
F1
F2
F3
F4
F5
F6
F7
F8
F0
SMALLER SIZE
LARGER SIZE

FIG. 3

TYPE \ SIZE	1	2	3	4	5	6	7	8
A.CHIPPING	X	X	O	O	O	O	O	O
B.PROJECTION	X	X	X	O	O	O	O	O
C.SHORT-CIRCUITING	X	X	X	X	O	O	O	O
D.LINE BREAKAGE	X	X	O	O	O	O	O	O
E.ISOLATED RESIDUE	X	X	X	X	X	O	O	O
F.ISOLATED PH	X	O	O	O	O	O	O	O

FIG. 4A

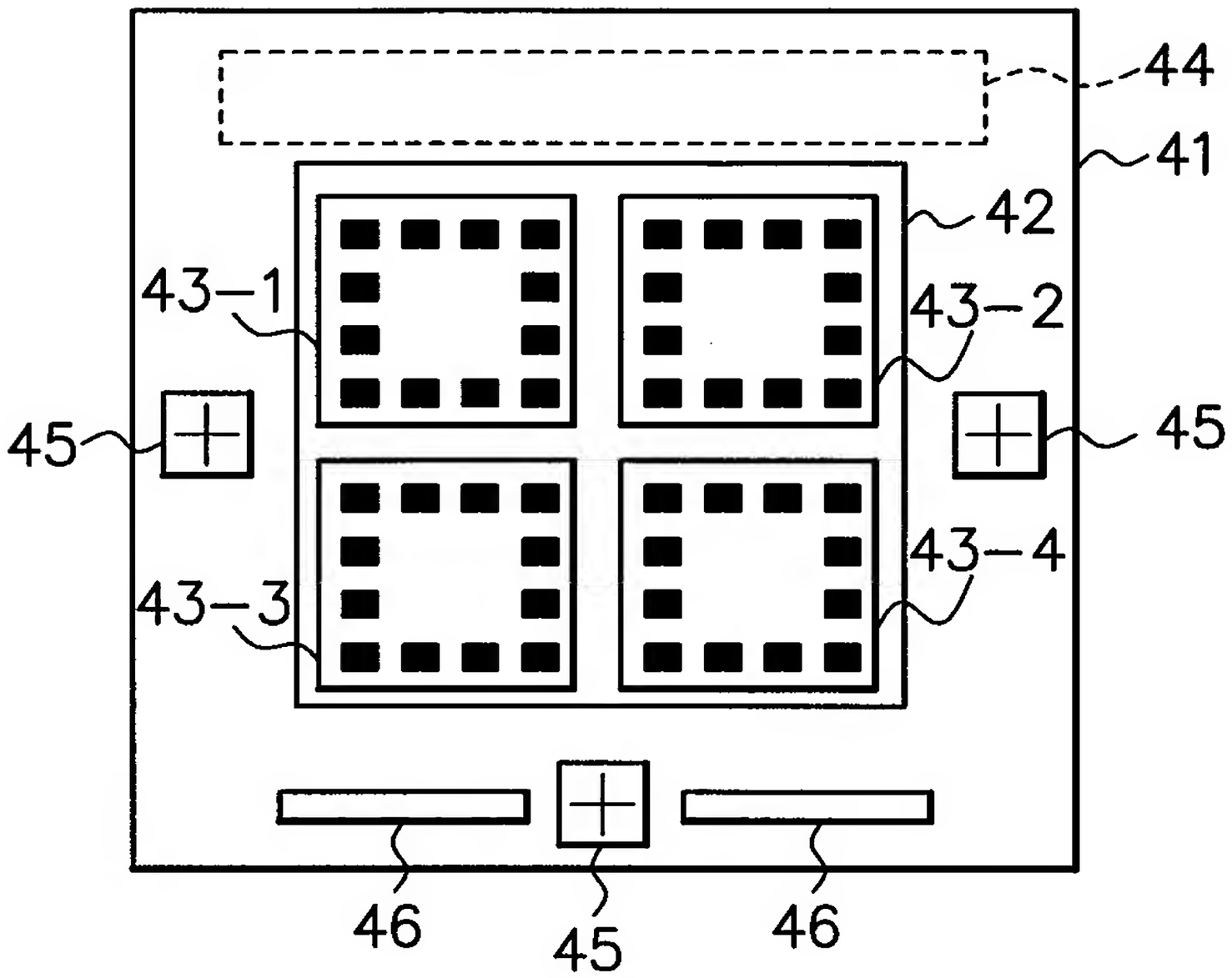


FIG. 4B

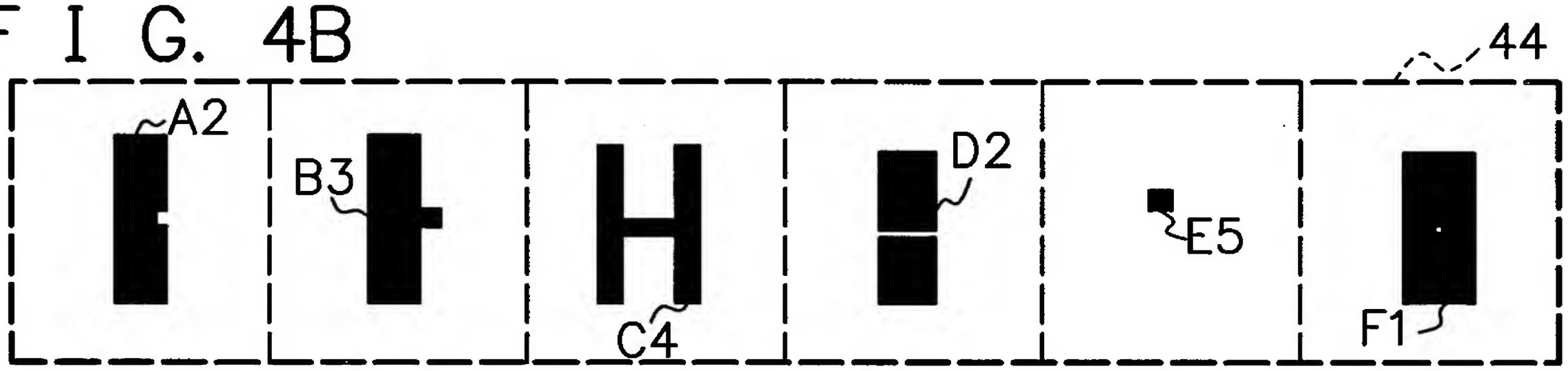
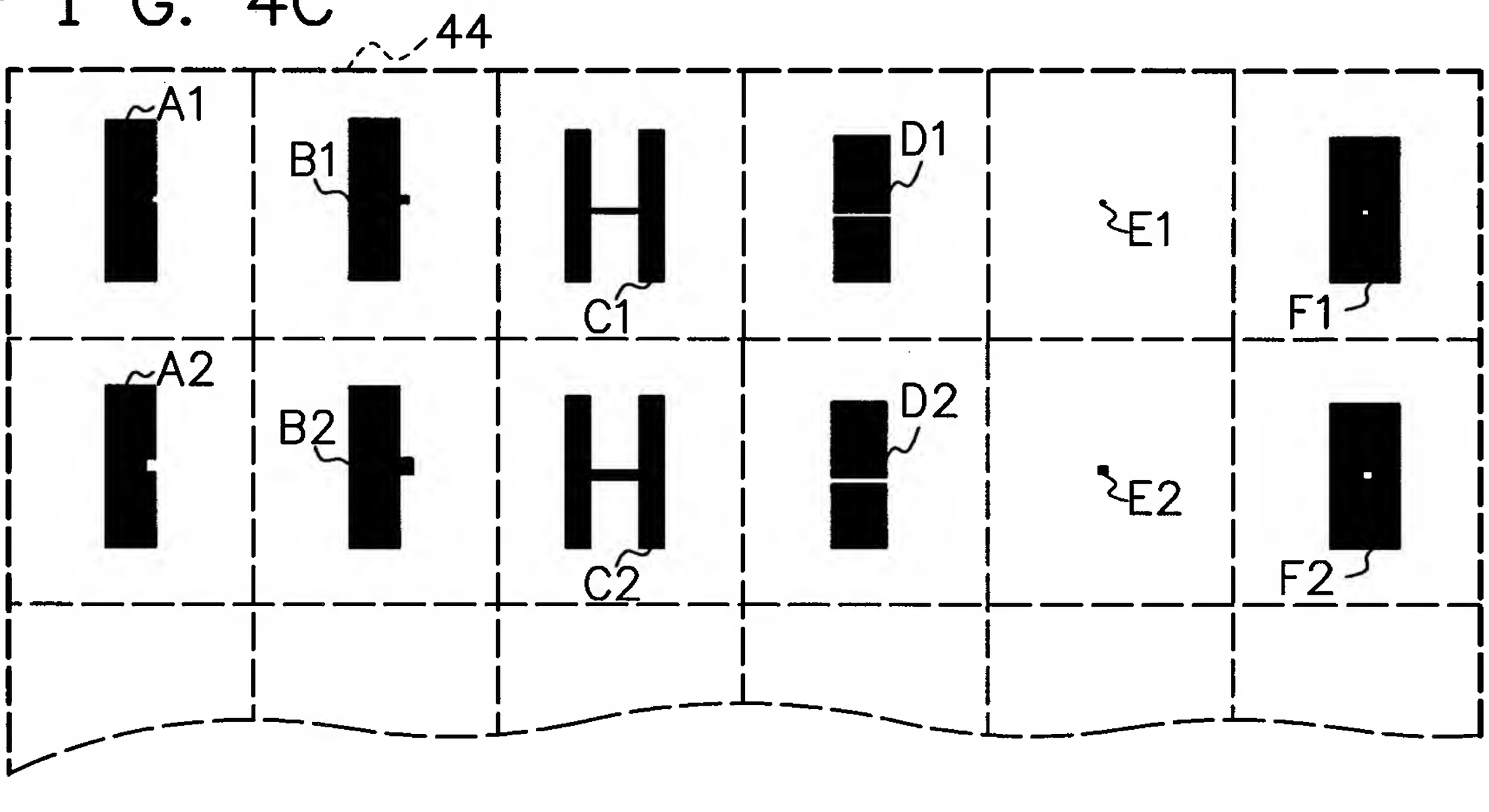


FIG. 4C



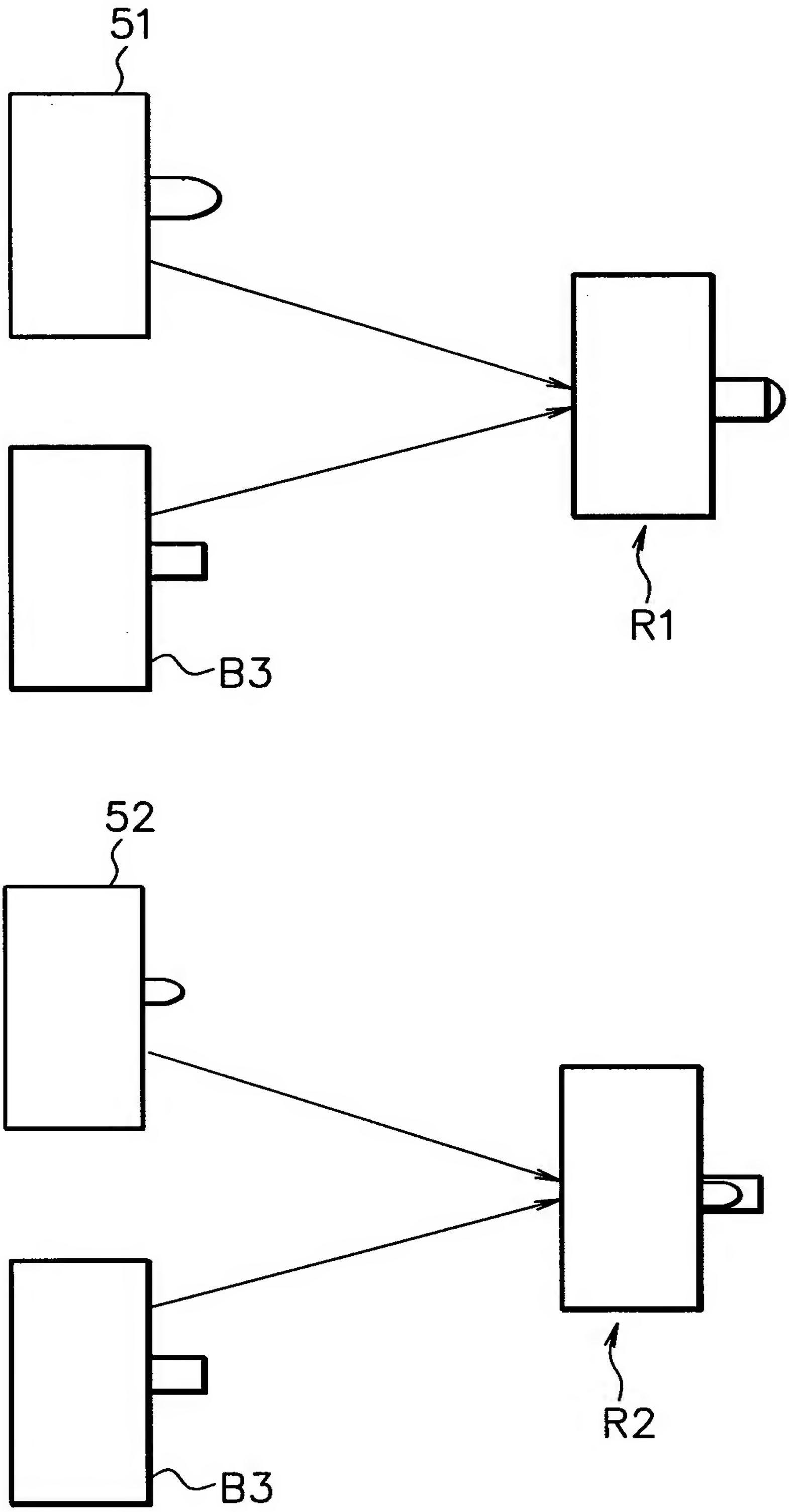


FIG. 5A

FIG. 5B

F I G. 6

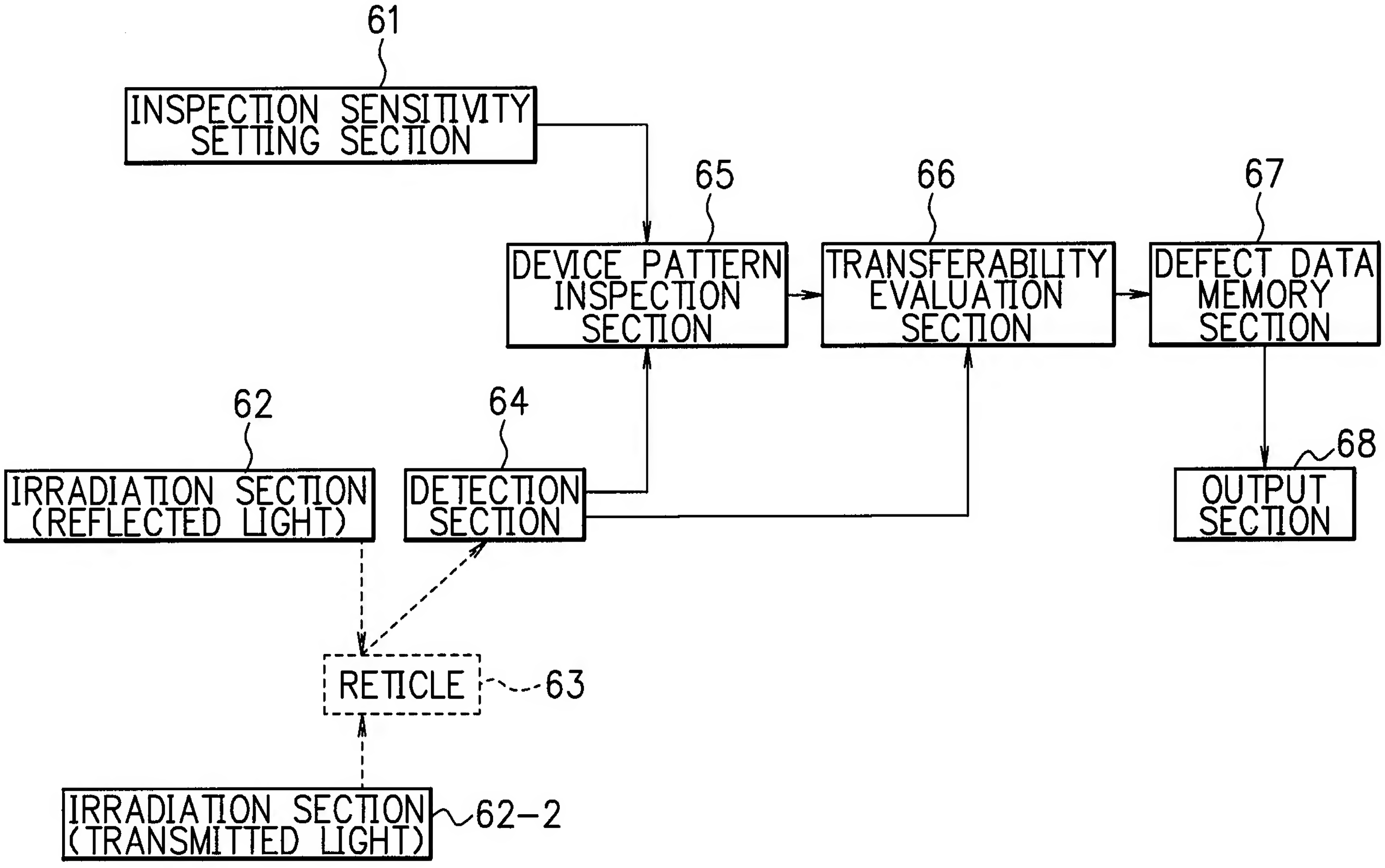

61
INSPECTION SENSITIVITY SETTING SECTION
65
DEVICE PATTERN INSPECTION SECTION
66
TRANSFERABILITY EVALUATION SECTION
67
DEFECT DATA MEMORY SECTION
62
IRRADIATION SECTION (REFLECTED LIGHT)
64
DETECTION SECTION
68
OUTPUT SECTION
RETICLE
63
IRRADIATION SECTION (TRANSMITTED LIGHT)
62-2

FIG. 7A
PRIOR ART

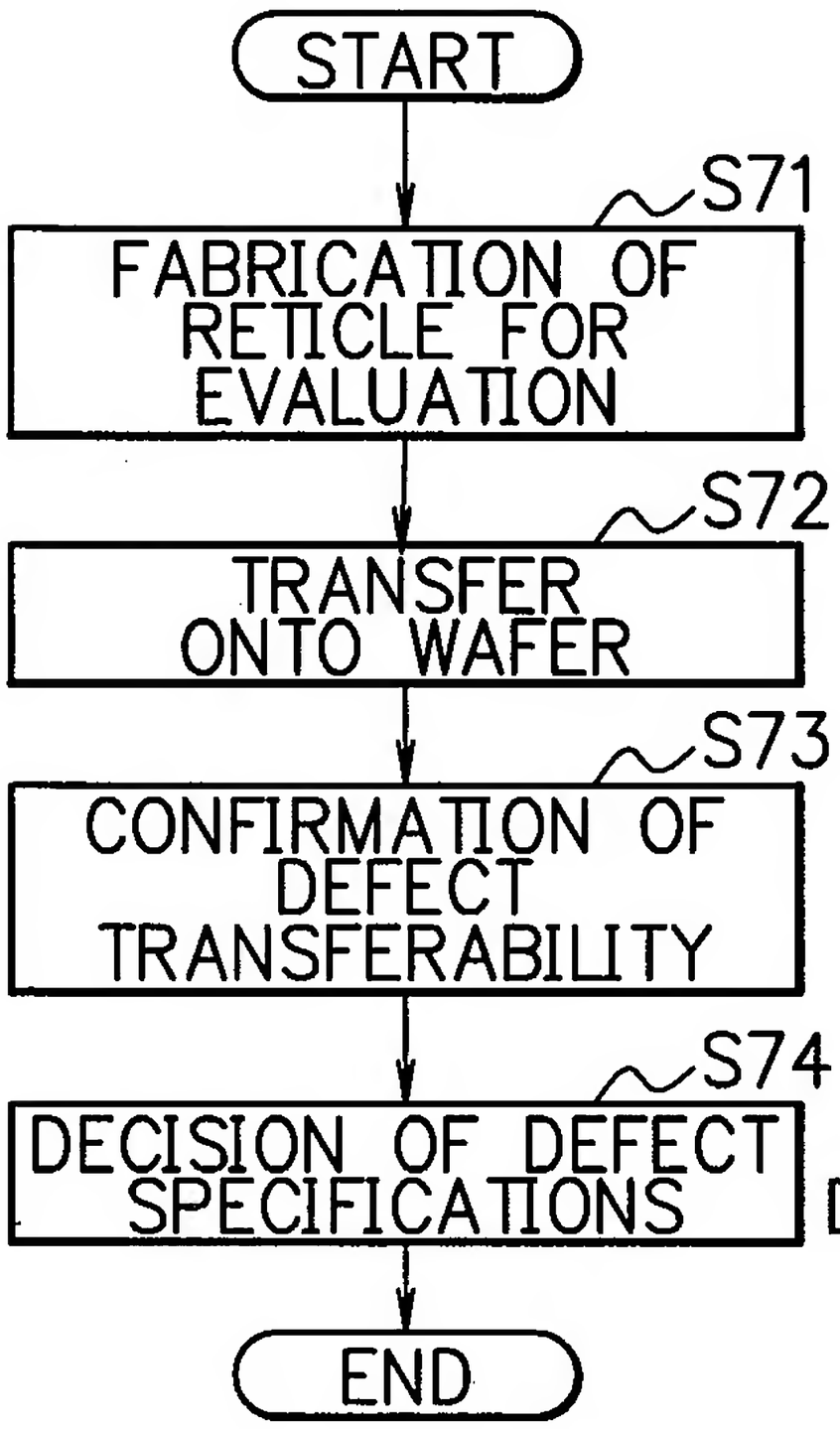


FIG. 7B
PRIOR ART

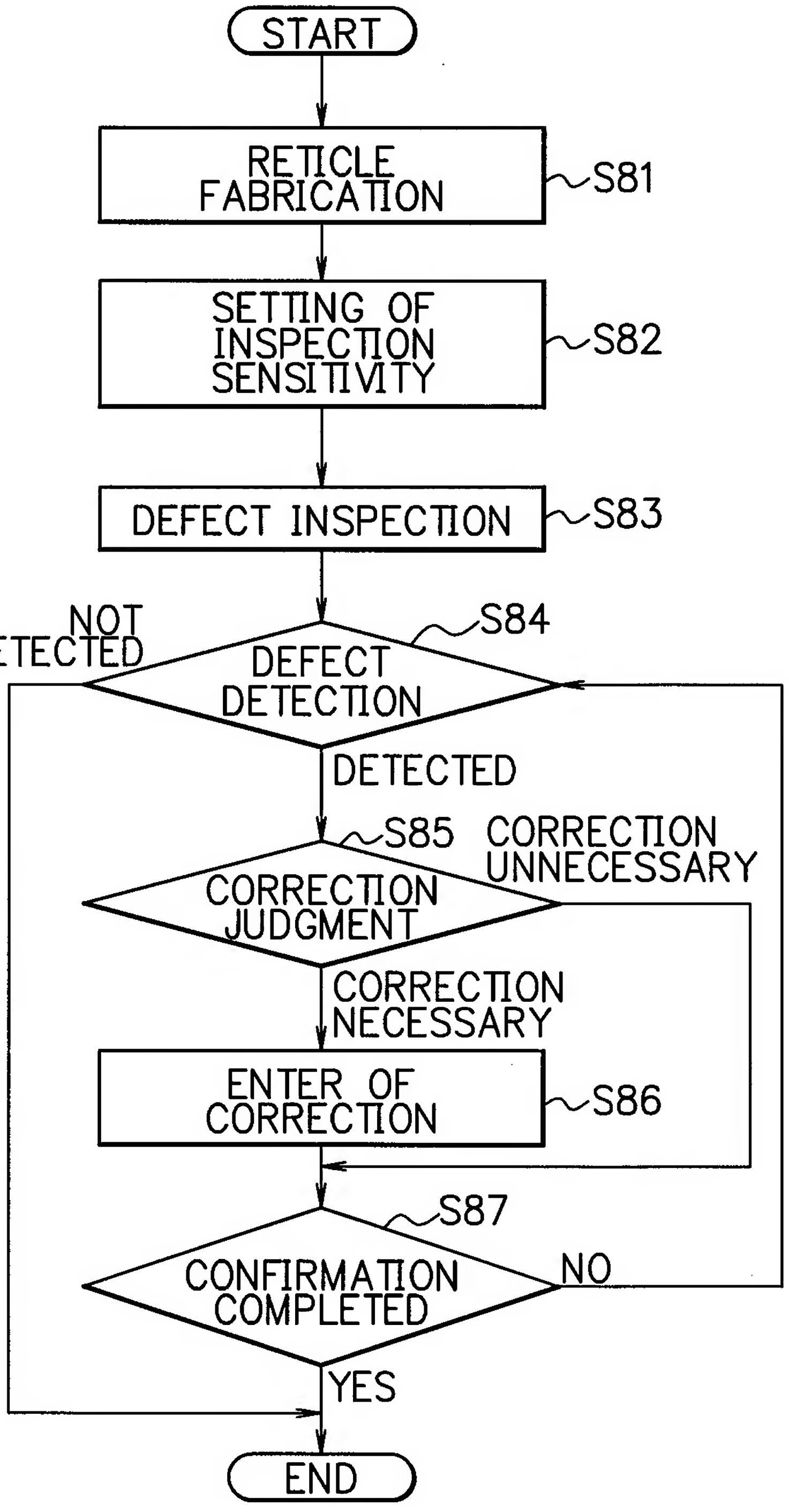
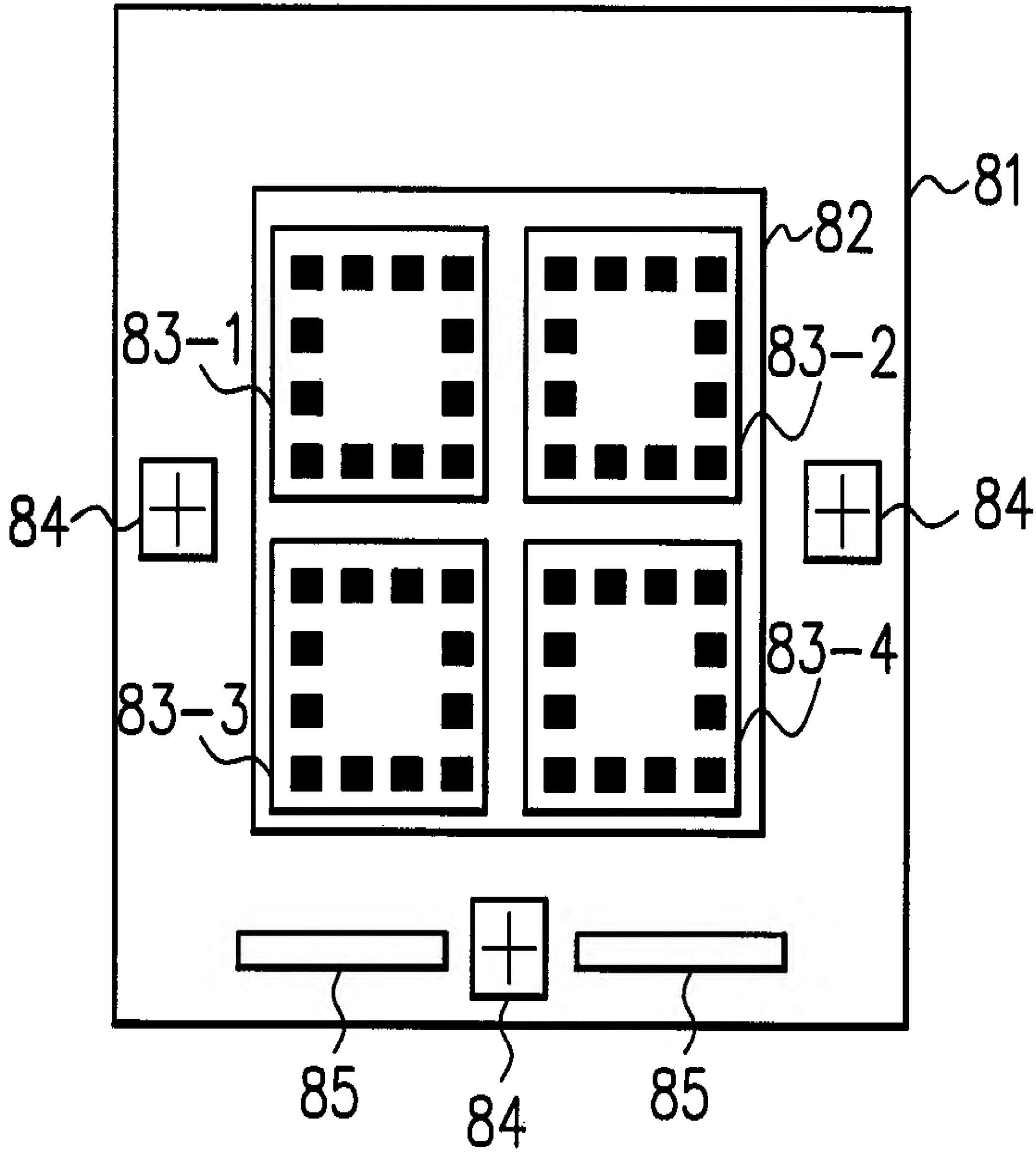



FIG. 8 PRIOR ART